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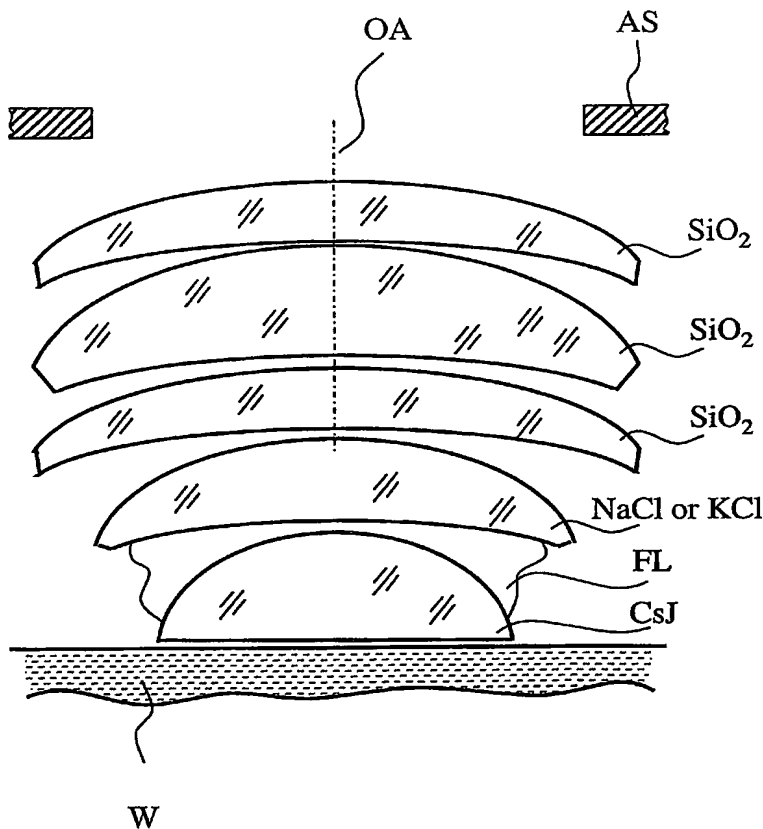
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(54) Title: **MICROLITHOGRAPHY PROJECTION OBJECTIVE WITH CRYSTAL LENS**



(57) Abstract: Very high aperture microlithography projection objectives operating at the wavelengths of 248 nm, 193 nm and also 157 nm, suitable for optical immersion or near-field operation with aperture values that can exceed 1.4 are made feasible with crystalline lenses and crystalline end plates P of NaCl, KCl, KJ, RbJ, CsJ, and MgO, YAG with refractive indices up to and above 2.0. These crystalline lenses and end plates are placed between the system aperture stop AS and the wafer W, preferably as the last lenses on the image side of the objective.



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- as to the applicant's entitlement to claim the priority of the earlier application (Rule 4.17(iii)) for all designations
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